

# P-Channel 100-V (D-S) MOSFET

PRODUCT SUMMARY						
V <sub>DS</sub> (V)	$R_{DS(on)}(\Omega)$		Q <sub>g</sub> (Typ.)			
- 100	0.160 at V <sub>GS</sub> = - 10 V	- 2.5 <sup>c</sup>	23.2 nC			
	0.200 at V <sub>GS</sub> = - 4.5 V	- 2.3 <sup>c</sup>	23.2 110			

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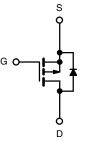
#### **FEATURES**

- Trench Power MOSFET
- 100% R<sub>q</sub> and UIS Tested



#### **APPLICATIONS**

- Active Clamp in Intermediate DC/ DC Power Supplies
- H-Bridge High Side Switch for Lighting Application



P-Channel MOSFET

Parameter	Symbol	Limit	Unit		
Drain-Source Voltage	V <sub>DS</sub>	- 100	V		
Gate-Source Voltage	V <sub>GS</sub>	± 20	v		
	T <sub>C</sub> = 25 °C		- 2.5		
Continuous Drain Current (T <sub>.I</sub> = 150 °C)	T <sub>C</sub> = 70 °C		- 2.3		
Continuous Diam Current (1) = 150 °C)	T <sub>A</sub> = 25 °C	- I <sub>D</sub> -	- 2 <sup>a, b</sup>		
	T <sub>A</sub> = 70 °C		- 1.6 <sup>a, b</sup>		
Pulsed Drain Current	I <sub>DM</sub>	- 15	A		
Continuous Source Drain Diada Current	T <sub>C</sub> = 25 °C	1-	- 4.9		
Continuous Source-Drain Diode Current	T <sub>A</sub> = 25 °C	ls =	- 2.5 <sup>a, b</sup>		
Avalanche Current	L = 0.1 mH	I <sub>AS</sub>	- 15		
Single-Pulse Avalanche Energy	L = 0.1 IIIH	E <sub>AS</sub>	11.25	mJ	
	T <sub>C</sub> = 25 °C		5.9		
Mayimum Dawar Dissination	T <sub>C</sub> = 70 °C		3.8	w	
Maximum Power Dissipation	T <sub>A</sub> = 25 °C	P <sub>D</sub>	3.1 <sup>a, b</sup>	vv	
	T <sub>A</sub> = 70 °C		2 <sup>a, b</sup>		
Operating Junction and Storage Temperature Range	T <sub>J</sub> , T <sub>stg</sub>	- 55 to 150	°C		

#### Notes:

- a. Surface mounted on 1" x 1" FR4 board.
- b. t = 10 s.
- c. Based on  $T_C$  = 25 °C.

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient <sup>a, b</sup>	t ≤ 10 s	R <sub>thJA</sub>	33	40	°C/W	
Maximum Junction-to-Foot (Drain)	Steady State	R <sub>thJF</sub>	17	21	- C/VV	

#### Notes:

- a. Surface mounted on 1" x 1" FR4 board.
- b. Maximum under steady state conditions is 80  $^{\circ}\text{C/W}.$



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static						
Drain-Source Breakdown Voltage	$V_{DS}$	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$	- 100			V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$			- 165		mV/°C
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$			- 6.6		mv/°C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_D = -250 \mu A$	- 1		- 3	V
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
Zoro Coto Voltago Drain Current	1	V <sub>DS</sub> = - 100 V, V <sub>GS</sub> = 0 V			- 1	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = - 100 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 55 °C			- 10	μΑ
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge -5 \text{ V}, V_{GS} = -10 \text{ V}$	- 8			Α
Durin Course Co Olata Basistana a	P	V <sub>GS</sub> = - 10 V, I <sub>D</sub> = - 2 A	0.160			
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	V <sub>GS</sub> = - 4.5V, I <sub>D</sub> = - 1.5 A		0.200		Ω
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = - 15 V, I <sub>D</sub> = 2 A		12		S
Dynamic <sup>b</sup>						
Input Capacitance	C <sub>iss</sub>			1190		pF
Output Capacitance	C <sub>oss</sub>	$V_{DS} = -50 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		61		
Reverse Transfer Capacitance	C <sub>rss</sub>			42		
Total Cata Charge		$V_{DS} = -50 \text{ V}, V_{GS} = -10 \text{ V}, I_D = -2 \text{ A}$		27.5	42	
Total Gate Charge				23.2	35	~C
Gate-Source Charge	Q <sub>gs</sub>	$V_{DS} = -50 \text{ V}, V_{GS} = -6 \text{ V}, I_{D} = -2 \text{ A}$		5.4		nC
Gate-Drain Charge	Q <sub>gd</sub>			8.4		
Gate Resistance	R <sub>g</sub>	f = 1 MHz		6.1	9.2	Ω
Turn-On Delay Time	t <sub>d(on)</sub>			20	30	
Rise Time	t <sub>r</sub>	$V_{DD} = -75 \text{ V}, R_{L} = 25 \Omega$		95	145	1
Turn-Off DelayTime	t <sub>d(off)</sub>	$I_D \cong -3 \text{ A}, V_{GEN} = -6 \text{ V}, R_g = 1 \Omega$		38	60	
Fall Time	t <sub>f</sub>			34	51	
Turn-On Delay Time	t <sub>d(on)</sub>			11	18	ns
Rise Time	t <sub>r</sub>	$V_{DD} = -75 \text{ V}, R_{L} = 25 \Omega$		28	42	
Turn-Off DelayTime	t <sub>d(off)</sub>	$I_D \cong -2 \text{ A}, V_{GEN} = -10 \text{ V}, R_g = 1 \Omega$		52	78	
Fall Time	t <sub>f</sub>			35	53	
<b>Drain-Source Body Diode Characterist</b>	ics					
Continuous Source-Drain Diode Current	I <sub>S</sub>	T <sub>C</sub> = 25 °C			- 13	۸
Pulse Diode Forward Current <sup>a</sup>	I <sub>SM</sub>				- 15	Α
Body Diode Voltage	$V_{SD}$	I <sub>S</sub> = - 2 A		- 0.8	- 1.2	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>			65	90	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	L_ = 4 A dl/dt = 100 A/vo T = 25 °C		180	270	nC
Reverse Recovery Fall Time	t <sub>a</sub>	$I_F = -4 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 °C$		45		ns
Reverse Recovery Rise Time	t <sub>b</sub>			20		

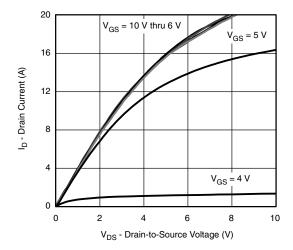
#### Notes:

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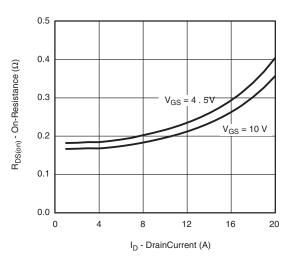
- a. Pulse test; pulse width  $\leq 300~\mu s,$  duty cycle  $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

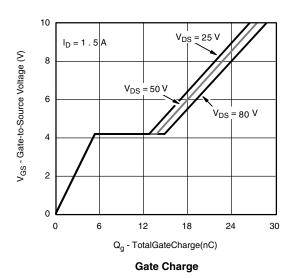




#### **Output Characteristics**



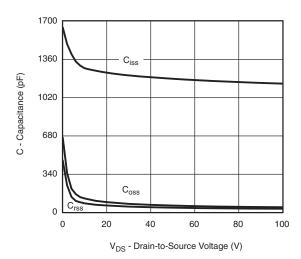
#### On-Resistance vs. Drain Current and Gate Voltage



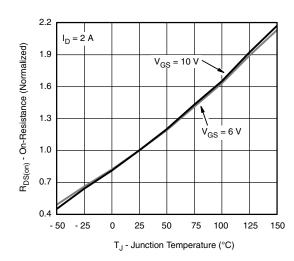
2.0
1.6
1.2
0.8
T<sub>C</sub> = 125 °C

0.4
T<sub>C</sub> = 25
T<sub>C</sub> = -55 °C

V<sub>GS</sub> - Gate-to-Source Voltage (V) **Transfer Characteristics** 

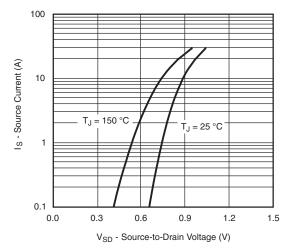


Capacitance

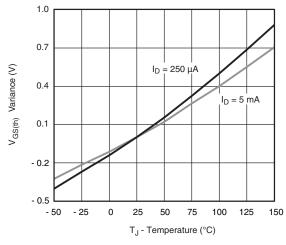


On-Resistance vs. Junction Temperature

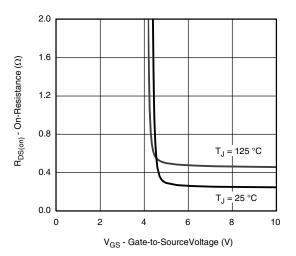




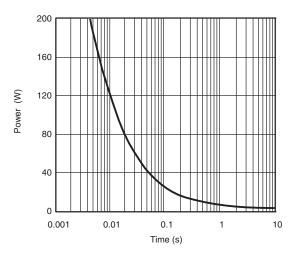
#### Source-Drain Diode Forward Voltage



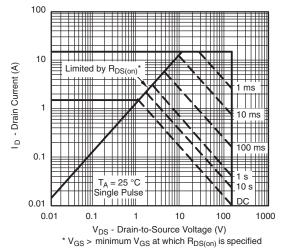
**Threshold Voltage** 



On-Resistance vs. Gate-to-Source Voltage

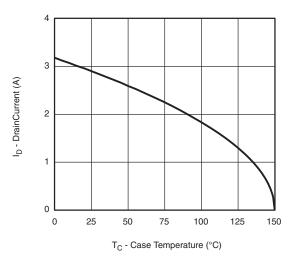


Single Pulse Power, Junction-to-Ambient

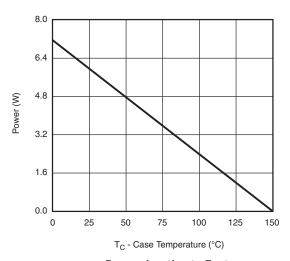


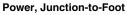
Safe Operating Area, Junction-to-Ambient

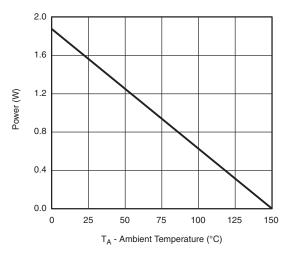




#### **Current Derating\***



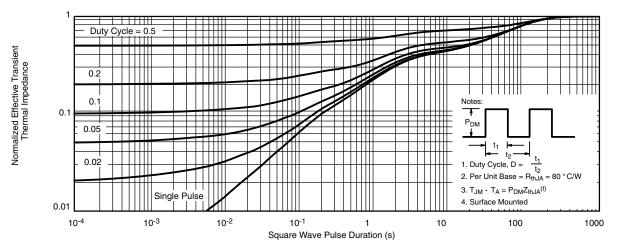




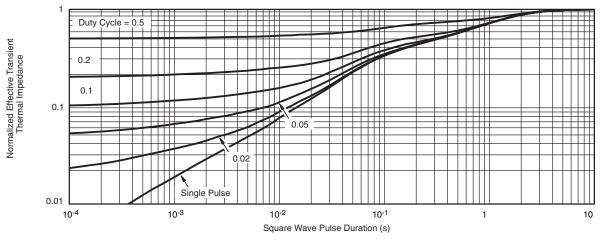
Power, Junction-to-Ambient

<sup>\*</sup> The power dissipation  $P_D$  is based on  $T_{J(max.)} = 150$  °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





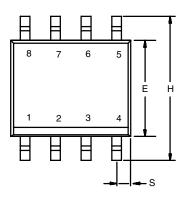
Normalized Thermal Transient Impedance, Junction-to-Ambient



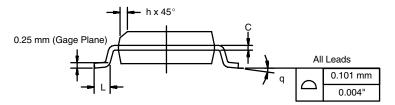
Normalized Thermal Transient Impedance, Junction-to-Foot



SOIC (NARROW): 8-LEAD JEDEC Part Number: MS-012







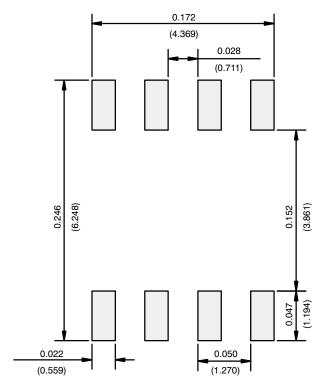
	MILLIMETERS INC			HES	
DIM	Min	Max	Min	Max	
Α	1.35	1.75	0.053	0.069	
A <sub>1</sub>	0.10	0.20	0.004	0.008	
В	0.35	0.51	0.014	0.020	
С	0.19	0.25	0.0075	0.010	
D	4.80	5.00	0.189	0.196	
Е	3.80	4.00	0.150	0.157	
е	1.27 BSC		0.050 BSC		
Н	5.80	6.20	0.228	0.244	
h	0.25	0.50	0.010	0.020	
L	0.50	0.93	0.020	0.037	
q	0°	8°	0°	8°	
S	0.44	0.64	0.018	0.026	
ECN: C 06527 Pay L 11 Cap 06					

ECN: C-06527-Rev. I, 11-Sep-06

DWG: 5498



## **RECOMMENDED MINIMUM PADS FOR SO-8**



Recommended Minimum Pads Dimensions in Inches/(mm)



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